

# NEOSEM

## Supported Protocols

- PCIe 2.0, PCIe 3.0
- SATA 3/6 Gbps
- SAS 3/6/12 Gbps
- AHCI, NVMe

## Supported Form Factors

- Edge Card (AIC)  
FHHL, HHHL
- 1.8", 2.5", 3.5"
- U.2
- mSATA
- M.2

## System Scalability

- **F-8A (Ambient)**  
Bench-top Tester  
Up to 4 Parallel DUTs
- **F-60B (+10C to +85C)**  
1-zone Chamber  
Up to 120 Parallel DUTs(AIC)  
Up to 240 Parallel DUTs(M.2)
- **F-60E (-34C to +85C)**  
1-zone Chamber  
Up to 192 Parallel DUTs(AIC)  
Up to 384 Parallel DUTs(M.2)

## NEOSEM Technology Inc

[www.neosemtech.com](http://www.neosemtech.com)  
[sales@neosemtech.com](mailto:sales@neosemtech.com)

(408) 643-7000  
1965 Concourse Dr.  
San Jose, CA 95131

# F-60E SSD/HDD Test System



## F-60E Environmental Chamber Test System

Neosem's F-60E Environmental Test system is designed for ongoing reliability and qualification testing by delivering accurate testing with consistency over a wide range of temperature. This test system will start and manage the device test, synchronize the temperature with testing, gather and organize test history and test results, and provide direct device access for deep analysis and troubleshooting. The environmental chamber system provides four-corner testing on parameters such as temperature(Hot and Cold) and Voltage

## Key Features

- Tailored to HDD, SSD or PCIe Testing with SAS, SATA, AHCI, NVMe plus Backdoor Serial interfaces
- Programmable power margining per DUT with current and voltage measurement read-back
- Turnkey solution, featuring Neosem's Andromeda operating software
- User-friendly GUI allows for easy test control (start/stop) and monitoring (status) of all Device Under Test (DUT) on one screen
- Provides characterization data such as performance, measurement, throughput, IOPs, thermal and power consumption
- GUI allows intuitive drill down monitoring from scripts level through DUT interface commands and down to bit level write and operations
- Comprehensive library of engineering, reliability, quality and production test scripts designed for HDD, SSD and PCIe devices

# F-60E SSD Test System

# NEOSEM

## Product Specifications

### Mechanical

- Exterior Dimensions: 83" wide x 81" tall x 54" deep

### Input Power

- 220, 230 Volts 3 Phase (Optional international voltage available)

### Software

- Test results are delivered in clear, detailed reports and graph
- Test script development tools
- GUI driven test control platform
- Debug through interactive shell command interface
- Individually captured information for every DUT
- Run multiple tests, simultaneously
- API for user-defined plug-ins
- Python/Java Support
- SNIA and JEDEC Compliance Test



### Applications

- Production Testing (Factory)
- Qualification
- Quality Assurance
  - Reliability Demonstration Testing (RDT)
  - Ongoing Reliability Testing (ORT)
  - Design Verification Testing (DVT)



## Supported Protocols

- HDD 2.5" , 3.5"
- PCIe 2.0, PCIe 3.0
- SATA 3/6 Gbps
- SAS 3/6/12 Gbps
- AHCI, NVMe

## Supported Form Factors

- Edge Card (AIC)  
FHHL, HHHL
- 1.8", 2.5", 3.5"
- U.2
- mSATA
- M.2

## System Scalability

- **F-8A ( Ambient )**  
Bench-top Tester  
Up to 4 Parallel DUTs
- **F-60B ( +10C to +85C )**  
1-zone Chamber  
Up to 120 Parallel DUTs(AIC)  
Up to 240 Parallel DUTs(M.2)
- **F-60E ( -34C to +85C )**  
1-zone Chamber  
Up to 192 Parallel DUTs(AIC)  
Up to 384 Parallel DUTs(M.2)

## F-60E Tester System Specifications

SSD ( 2.5" ) 256 DUTs

HDD ( 3.5" ) 64 DUTs

PCIe SSD 192 DUTs ( AIC )  
384 DUTs ( M.2 )

Chamber Temperature Range - 34 C to + 85 C

Test Application Development P25 Script & JAVA Support

Tester Input Power 208-220V AC – 50 to 60 hz 3 Phase

Tester Operating Temperature Range 18 to 28 Degree C – Air cooled

Tester Software Andromeda Operating S/W

## NEOSEM Technology Inc

[www.neosemtech.com](http://www.neosemtech.com)  
[sales@neosemtech.com](mailto:sales@neosemtech.com)

(408) 643-7000  
1965 Concourse Dr.  
San Jose, CA 95131